

<b>Notice of References Cited</b>	Application/Control No. 10/805,365	Applicant(s)/Patent Under Reexamination TANAKA ET AL.	
	Examiner VanThu Nguyen	Art Unit 2824	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0035329 A1	02-2003	Tailliet et al.	365/200
*	B	US-6,643,193 B2	11-2003	Yamaki et al.	365/189.09
*	C	US-6,038,172 A	03-2000	Rai et al.	365/185.2
*	D	US-5,852,578 A	12-1998	Hoang, Loc B.	365/185.28
*	E	US-5,818,761 A	10-1998	Onakado et al.	365/185.18
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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